

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any referred to as being attached or enclosed) is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on the date indicated below.

Dated: 7/28/06

Linda Major

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application for:

Sandeep Bhatia

Serial No.: **10/718,445**

Filing Date: **November 19, 2003**

For: **Dual Scan Chain Design Method and Apparatus**

Confirmation No.: **9844**

Examiner: **John J. Tabone, Jr.**

Group Art Unit: **2138**

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with 37 CFR §§ 1.97 and 1.98, the items identified in this Information Disclosure Statement (IDS) are being brought to the attention of the Office. The items are listed on the attached form PTO/SB/08B. The Examiner is requested to make these documents of record.

The items identified in this IDS may or may not be "material" pursuant to 37 CFR § 1.56. The submission thereof by Applicant(s) is not to be construed as an admission that any such patent, publication or other information referred to therein is material or considered to be material (37 CFR § 1.97(h)), or even qualifies as "prior art" under 35 USC § 102 with respect to this invention unless specifically designated by Applicant(s) as such.

1. Timing of the Information Disclosure Statement:

☐ This IDS is believed to be timely in that it is being submitted under 37 CFR § 1.97(b), that is (1) with the new patent application submitted herein (37 CFR § 1.97(a)); or (2) within

three months of the filing date of the application, which is not a continued prosecution application filed under § 1.53(d) or (3) within three months of entry of the national stage as set forth in 37 CFR § 1.491; or (4) before the mailing of a first Office action on the merits; or (5) before the mailing of a first Office action after filing a request for continued examination under § 1.114. Thus, no fee is required.

- ☐ However, if the undersigned is in error in this regard, Applicant(s) respectfully requests that the Office consider this IDS as filed under 37 CFR § 1.97(c), if applicable, and charge the fee due under 37 CFR § 1.17(p) to the deposit account referenced below.
- ☐ However, if the undersigned is in error in this regard, Applicant(s) respectfully requests that the Office consider this IDS as filed under 37 CFR § 1.97(c), if applicable, and a statement under 37 CFR § 1.97(e) is included below, thus no fee is required.
- ☒ This IDS is being submitted under 37 CFR § 1.97(c), that is after mailing of a first Office Action on the merits, but before a Final Action under 37 CFR § 1.113 or a Notice of Allowance under 37 CFR § 1.311.
 - ☒ Charge the fee due under 37 CFR § 1.17(p) to the deposit account referenced below.
 - ☐ The fee due under 37 CFR § 1.17(p) is being concurrently submitted with the filing of an electronic IDS submission. Thus, no additional fee is required.
 - ☐ A statement under 37 CFR § 1.97(e) is included below, thus no fee is required. In the event that this IDS is not received before a Final Action or a Notice of Allowance, then Applicant(s) respectfully requests that the Office consider the filing of these papers to be submitted under 37 CFR § 1.97(d) and charge the fee due under 37 CFR § 1.17(p) to the deposit account referenced below.
- ☐ This IDS is being submitted under 37 CFR § 1.97(d), that is after a Final Action under 37 CFR § 1.113 or a Notice of Allowance under 37 CFR § 1.311, but before payment of the issue fee. A statement under 37 CFR § 1.97(e) is included below. Charge the fee due under 37 CFR § 1.17(p) to the deposit account referenced below.
- ☐ This IDS is being submitted under 37 CFR § 1.97(i), that is after a Final Action under 37 CFR § 1.113 or a Notice of Allowance under 37 CFR § 1.311, but before payment of the issue fee.

STATEMENT UNDER 37 CFR § 1.97(e):

- ☐ That each item of information contained in the IDS was first cited in any communication

from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the IDS; or

☐ That no item of information contained in the IDS was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the IDS was known to any individual designated in 37 CFR § 1.56(c) more than three months prior to the filing of the IDS.

2. Copies of the Cited Items:

☒ Copies of all of the items listed on the attached form PTO/SB/08B are enclosed.

☐ Copies of only the following items listed on the attached forms PTO/SB/08B (Item Nos. *) are enclosed.

☐ Copies of the following items listed on the attached form PTO/SB/08A (Item Nos. * - *) are not enclosed. See 37 CFR 1.98(a)(2)(i).

☐ Copies of the following documents listed in PTO/SB/08A (Item Nos. *) and PTO/SB/08B (Item Nos. *) are not supplied as they were previously cited by the Office or submitted in Information Disclosure Statements in related applications (Application No. *, filed *) and relied upon in this application for an earlier filing date under 35 USC § 120. See 37 CFR § 1.98(d). The Examiner is requested to make these documents of record.

☐ Copies of the following items listed on the attached forms PTO/SB/08A (Item Nos. *) and PTO/SB/08B (Item Nos. *) were cited in a foreign examination report in a related case. A copy of the search report and the cited references not already of record in this application are attached hereto.

3. Concise Explanation of Relevance:

☒ A concise explanation of relevance of the items listed on form PTO/SB/08B is not given.

☐ A concise explanation of relevance of [some of] the items listed on forms PTO/SB/08A and PTO/SB/08B is in the form of an English language copy of a Search Report from a foreign

patent office, issued in a counterpart application, which refers to the relevant portions of the references (copy attached).

4. Related Applications:

☐ Applicant(s) brings to the Office's attention the following related application(s): U.S. Patent Application No. * filed *, now U.S. Patent No. *.

5. Conclusion:

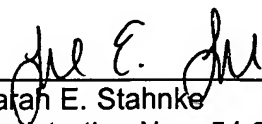
Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made, other than as described above; and
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

It is respectfully requested that the Examiner indicate consideration of the cited references by returning a copy of the attached forms PTO/SB/08B with initials or other appropriate marks. In the unlikely event that the transmittal letter is separated from this document and the U.S. Patent Office determines that an extension and/or other relief is required, Applicant(s) petitions for any required relief including extensions of time and authorizes the Commissioner to charge the cost of such petitions and/or other fees due in connection with the filing of this document to **Deposit Account No. 50-2518**, referencing **7035962001**. However, the Commissioner is not authorized to charge the cost of the issue fee to the Deposit Account.

Respectfully submitted,

Dated: July 28, 2006

By: 
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Substitute for form 1449B/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet

1

of

1

Complete if Known

Application Number	10/718,445
Filing Date	November 19, 2003
First Named Inventor	Sandeep Bhatia
Art Unit	2138
Examiner Name	John J. Tabone, Jr.
Attorney Docket Number	CA7035962001

NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	1	BALAKRISHNAN, K. J., et al., "Deterministic Test Vector Decompression in Software Using Linear Operations", Proceedings of the 21st IEEE VLSI Test Symposium, April 27 - May 1, 2003, pp. 225 - 231, IEEE, Los Alamitos, CA, USA.	
	2	BARDELL, P. H. et al., "Build-In-Test for VLSI: Pseudorandom Techniques", 1987, pp. 61-313, John Wiley and Sons, New York, USA.	
	3	BHATIA, S., "Test Compaction by Using Linear-Matrix Driven Scan Chains", Proceedings of the 18 th IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems, November 3 - 5, 2003, pp. 185 - 190, IEEE, USA.	
	4	BHATIA, S., "Test Compaction in a Parallel Access Scan Environment", Proceedings of the 6 th Asian Test Symposium (ATS '97), November 17 - 19, 1997, pp. 300 -305, IEEE, Los Alamitos, CA, USA.	
	5	HELLEBRAND, S., et al., "Generation of Vector Patterns Through Reseeding of Multiple-Polynomial Linear Feedback Shift Registers", Proceedings of the International Test Conference, 1992, pp. 120 -124, France.	
	6	HSU, F. F. et al., "A Case Study on the Implementation of the Illinois Scan Architecture", Proceedings of the International Test Conference; 2001, pp. 538 - 547, International Test Conference, Washington, D.C., USA.	
	7	KIEFER, G. et al., "Deterministic BIST with Multiple Scan Chains", Proceedings of the International Test Conference, 1998, pp. 1057 - 1064, International Test Conference, Washington, D.C., USA.	
	8	KRISHNA, C.V. et al., "Reducing Test Data Volume Using LFSR Reseeding with Seed Compression", Proceedings of the International Test Conference, 2002, pp. 321 - 330, International Test Conference, Washington, D.C., USA.	
	9	McCLUSKEY, E. J., "Test Data Compression", Design & Test of Computers, March - April 2003, pp. 76 - 87, Volume 20, Issue 2, IEEE Computer Society and the IEEE Circuits and Systems Society, USA.	
	10	RAJSKI, J. et al., "Embedded Deterministic Test for Low Cost Manufacturing Test", Proceedings of the International Test Conference, 2002, pp. 310 - 310, International Test Conference, Washington, D. C., USA.	

Examiner
SignatureDate
Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.